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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	Unassigned
				Filing Date	September 12, 2003
				First Named Inventor	Takayuki HISAKA
				Group Art Unit	Unassigned
				Examiner Name	Unassigned
Sheet	1	of	1	Attorney Docket Number	402775/AOYAMA

FOREIGN PATENT DOCUMENTS								
Examiner Initials	Doc. No.	Foreign Patent Document			Name of Patentee or Applicant	Date of Publication	Translation	
		Office	Application or Patent Number	Kind Code			Yes	No**
gn	A 1	JP	6-244218		SUMITOMO ELECTRIC IND LTD	9/2/1994		X+
cn	A 2	JP	9-205196		HITACHI CABLE LTD	8/5/1997		X+
cn	A 3	JP	9-246528		HITACHI CABLE LTD	9/19/1997		X+
ch	A 4	EPO	0 301 862		SONY CORP.	1/2/1989		X+

OTHER - NON PATENT LITERATURE DOCUMENTS								
Examiner Initials	Doc. No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number (s), publisher, city and/or country where published.					Translation	
							Yes	No**
a	A 5	C.S. WHELAN et al., "Low Noise $\text{In}_{0.32}(\text{AlGa})_{0.68}\text{As}/\text{In}_{0.43}\text{Ga}_{0.57}\text{As}$ Metamorphic HEMT on GaAs Substrate with 850 mW/mm Output Power Density", <i>IEEE Electron Letters</i> , January 2000, pp. 5-8; Vol. 21, No. 1.						
cn	A 6	J.C.M. HWANG, "Gradual Degradation Under RF Overdrive Of MESFETs and PHEMTs", <i>GaAs IC Symposium</i> , 1995, pp. 81-84.						
cn	A 7	Y.A. TKACHENKO et al., "Hot-Electron-Induced Degradation of Metal-Semiconductor Field-Effect Transistors", <i>GaAs IC Symposium</i> , 1994, pp. 259-262.						
cn	A 8	L. AUCCOIN et al., "PHEMT Reliability: The Importance of RF Life Testing", <i>GaAs MANTECH</i> , 1997, pp. 42-45.						

Examiner Signature		Date Considered	11-30-04
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- * A concise statement of relevance is being submitted in lieu of a translation. 37 CFR 1.98(a)(3).
 + An English-language equivalent/patent, or an English-language abstract, or an English-language version of the search report or action by a foreign patent office in a counterpart foreign application indicating the degree of relevance found by the foreign office is being submitted in lieu of a concise explanation of relevance under 37 CFR 1.98(a)(3).